

Substitute for Form 1449A/PTO				Complete if Known	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT				Application Number	10/642,305
(use as many sheets as necessary)				Filing Date	August 18, 2003
				First Named Inventor	Hongyong ZHANG et al.
				Art Unit	2811
				Examiner Name	D. Owens
Sheet	1	of	7	Attorney Docket Number	740756-2646

U.S. PATENT DOCUMENTS					
Examiner Initials	Chg No.	U.S. Patent Document Number - Kind Code (if known)	Publication Date MM-DD-YYYY	Name of Patent or Applicant of Cited Document	Page, Col Reference Line Where Appears
(R)W		US-4,680,609	07/14/1987	Calder et al.	
		US-5,105,245	04/14/1992	Riemenschneider et al.	
		US-3,933,530	01/20/1976	Mueller et al.	
		US-4,027,380	06/07/1977	Deal et al.	
		US-4,403,239	09/06/1983	Yamazaki	
		US-4,451,838	05/29/1984	Yamazaki et al.	
		US-4,502,204	03/05/1985	Togashi et al.	
		US-4,746,628	05/24/1988	Takafuji et al.	
		US-5,008,218	04/16/1991	Kawachi et al.	
		US-5,060,036	10/22/1991	Choi	
		US-5,076,666	12/31/1991	Katayama et al.	
		US-4,851,363	07/25/1989	Troxell et al.	
		US-4,748,131	05/31/1988	Zietlow	
		US-5,233,191	08/03/1993	Noguchi et al.	
		US-4,217,194	08/12/1980	Lubbers et al.	
		US-5,288,684	02/22/1994	Yamazaki et al.	
		US-4,404,735	09/20/1983	Sakurai	
		US-4,585,492	04/29/1986	Weinberg et al.	
		US-4,566,913	01/28/1986	Brodsky et al.	
		US-4,599,135	07/08/1986	Tsukakawa et al.	
		US-5,238,705	08/24/1993	Hayashi et al.	
		US-4,915,772	04/10/1990	Fechner et al.	
		US-5,495,353	02/27/1996	Yamazaki et al.	
		US-5,514,879	05/07/1996	Yamazaki	
		US-4,517,733	05/21/1985	Hamano	
		US-4,849,081	07/18/1989	Ross	
		US-5,523,240	06/04/1996	Zhang et al.	
		US-5,045,485	09/03/1991	Tanaka et al.	
		US-4,882,295	11/21/1989	Czubatyj et al.	
		US-4,968,638	11/06/1990	Wright et al.	
		US-5,180,690	01/19/1993	Czubatyj et al.	
(R)W		US-4,693,759	09/13/1987	Noguchi et al.	
		US-4,459,739	07/17/1984	Shepherd et al.	

Examiner Signature	Douglas W. Owens	Date Considered	11/16/04
-----------------------	------------------	--------------------	----------

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not a conformance and not considered. Include copy of this form with next communication to applicant.

¹ Applicant's unique citation designation number (optional). ² See Kinds Codes of USPTO Patent Documents at www.uspto.gov or MPEP § 1.04. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.

¹ Applicant's unique citation designation number (optional). ² Applicant is to place a check mark here if English language Translation is attached.

NVA274468.1

BEST AVAILABLE COPY

<p>Substitute for Form 1449A/PTO</p> <p>INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)</p>				<i>Complete if Known</i>	
Sheet	2	of	7	Application Number	10/642,305
				Filing Date	August 18, 2003
				First Named Inventor	Hongyong ZHANG et al.
				Art Unit	2811
				Examiner Name	D. Owens
				Attorney Docket Number	740756-2646

U.S. PATENT DOCUMENTS

**Examiner
Signature**

Donald R. Davis

Date Considered

11/10/04

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹ Applicant's unique citation designation number (optional). ² See Kinds Codes of USPTO Patent Documents at www.uspto.gov or MPEP 101.04. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.

¹ Applicant's unique citation designation number (optional). ² Applicant is to place a check mark here if English language Translation is not used.

MYA374469.1

Substitute for Form 1449A/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(use as many sheets as necessary)</i>				<i>Complete if Known</i>		
				Application Number	10/642,305	
				Filing Date	August 18, 2003	
				First Named Inventor	Hongyong ZHANG et al.	
				Art Unit	2811	
				Examiner Name	D. Owens	
Sheet	3	of	7	Attorney Docket Number	740756-2646	
FOREIGN PATENT DOCUMENTS						
Examiner Initials*	Cite No. ¹	Previous Patent Document		Name of Examiner or Applicant of Cited Document	Page, Column, Line, Where Relevant Passages or Relevant Figures Appear	T ²
		Country Code ³	Number ⁴ (if known)			
<i>DWG</i>	JP 62-211165		09/1987			Abstract
	JP 02-77127		03/16/1990			Abstract
	FR 2573916		05/30/1986			
	GB 2169442 A		07/09/1986			
	JP 01-35959		02/1989			
	JP 61-183970		08/16/1986			
	JP 62-039068		02/20/1987			
	JP 01-283873		11/15/1989			
	JP 02-303030		12/17/1990			
	JP 60-043869		01/08/1985			
	JP 02-159069		06/19/1990			
	JP 02-148831		06/07/1990			
	JP 01-187814		07/27/1989			
	JP 60-245174		12/04/1985			
	JP 60-018913		01/31/1983			
	JP 62-285469		12/11/1987			
	JP 62-285470		12/11/1987			
	JP 01-209764		08/23/1989	Kato		Ex. Cited
	JP 02-090568		03/30/1990	Suyama		Ex. Cited
	EP 436 741		07/17/1991	Ando et al.		Ex. Cited
	WO 91/02102		02/21/1991	Ando et al.		Ex. Cited
	JP 62-285469		03/25/1988	Abe		Ex. Cited
	JP 62-244165		10/24/1987			Abstract
	JP 01-187873		07/27/1989			Abstract
	JP 01-287964		11/20/1989			Abstract & Full
	JP 01-042864		02/15/1989			Abstract
	JP 01-268064		10/25/1989			Full
	JP 02-211637 A		08/1990			
	JP 57-132191		08/16/1982			
	JP 62-119974		06/01/1987			
	JP 58-164268		09/29/1983	Takeo		Abstract
	JP 61-198678		09/03/1986	Yanagisawa		Abstract
	JP 63-036574		02/17/1988	Konishi et al.		Abstract
	JP 55-163848		12/20/1980			Full
	Examiner Signature	<i>Douglas R. Owens</i>		Date Considered	11/10/04	

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Substitute for Form 1449A/PTO				<i>Complete if Known</i>	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(use as many sheets as necessary)</i>				Application Number	10/642,305
Sheet	4	of	7	Filing Date	August 18, 2003
				First Named Inventor	Hongyong ZHANG et al.
				Art Unit	2811
				Examiner Name	D. Owens
				Attorney Docket Number	740756-2646

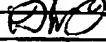
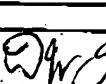
OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS			
Examiner Initials	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, card, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
DHg		T. TAKESHITA et al., "Study of ECR Hydrogen Plasma Treatment on Poly-Si Thin Film Transistors" Japanese Journal of Applied Physics, Vol. 27, No. 11, November 1988, pp. L2118-L2120, Tokyo, JP.	
		S. Wolf & R.N. Tauber, "Silicon Processing of the VLSI ERA", Lattice Press, 1286, pp. 168-199, 334-335, Vol. I.	
		J. Nulman et al., IEEE Electron Dev. Lett., EDL6, #5, 1985 P. 205-7, "RTP OF THIN GATE DIELECTRICS".	
		K.B. Kadyrakunov, et al., PHYS. STAT. SOL., A70, (1982), P.k15 "...PULSED ANNEALING OF Si-SiO ₂ INTERFACES".	
		D.L. Crosthwait, et al., LASER AND E-BEAM SOLID INTERACTIONS, PROC. MRI 1980, P.399, "...LASER IRRADIATION THERMAL OXIDES...".	
		S. Ghandhi, VLSI FABRICATION PRINCIPLES., 1983, Wiley & Sons, P. 388-391.	
		M. Morita et al., Appl. Phys. Lett., 49(86) 699 "F ENHANCED OXIDATION OF Si UNDER EXCIMER LASER...".	
		L. Jastrzebski, RCA Review, 44 (1983) 250, "Comparison of Different SOI Technologies: Assets and Liabilities, 1983.	
		J. Cordlandt et al., Solid St. Technol., 25(10)(1982) 153 (Abstract), "...RF sputtered SiC layers", October, 1982.	
		S. Suyama et al., IEEE Trans. Electron Dev., 34(10) (1987) 2124, "...MOSFET's Utilizing Oxygen-Argon Sputter-Deposited Gate Oxide Films", October, 1987.	
		T.I. Kamins et al., IEEE Electron Dev. Lett. Vol EDL-1, No. 8, 159 "Hydrogenation of transistors fabricated in Polycrystalline-Silicon Films", August, 1980.	
		Katoda, "Estimation of a Semiconductor by a Laser Raman Spectroscopy", Published by Tokyo University, 1988, pp. 67-75 (in Japanese with Concise English Statement).	
DHO		Baker et al., "The Influence of Fluorine on Threshold Voltage Instabilities In P+ Polysilicon gated P-Channel MOSFET's", IEEE, 1989, IEDM, pages 443-446.	

Examiner Signature	D. Owens	Date Considered	11/10/04
--------------------	----------	-----------------	----------

¹EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Substitute for Form 1449A/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(use as many sheets as necessary)</i>				<i>Complete if Known</i>	
				Application Number	10/642,305
				Filing Date	August 18, 2003
				First Named Inventor	Hongyong ZHANG et al.
				Art Unit	2811
				Examiner Name	D. Owens
				Attorney Docket Number	740756-2646
Sheet	3	of	7		

***EXAMINER:** Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO-1449 (Rev. 8-83)		U.S. Department of Com Patent and Trademark		Attorney Docket: 740736-2646		Serial No. 10/642,305		
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)						Sheet 6 of 7		
				Applicant: Hongyong ZHANG et al.				
				Filing Date: August 18, 2003		Group: 2811		
U.S. PATENT DOCUMENTS								
Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date (if appropriate)		
	4,377,421	03/22/83	Wada et al					
	4,561,906	12/31/85	Calder et al					
	4,619,034	10/28/86	Janning					
	4,651,408	03/24/87	MacElvoe et al					
	4,698,486	10/06/87	Sheets					
	4,814,292	03/21/89	Sasaki et al					
	4,847,211	07/11/89	Lee					
	4,882,295	11/21/89	Czubatyj et al					
	4,959,700	09/25/90	Yamazaki et al					
	4,698,638	11/06/90	Wright et al					
	4,998,152	03/05/91	Batey et al					
	5,061,642	10/29/91	Fujioka					
	5,070,379	12/03/91	Nomoto et al					
	5,141,885	08/25/92	Yoshida et al					
	5,198,379	03/30/93	Adan					
	5,208,476	05/04/93	Inoue					
	5,219,786	06/15/93	Noguchi					
	5,278,093	01/11/94	Yonehara					
	5,286,658	02/15/94	Shirakawa et al					
	5,329,140	07/12/94	Sera					
	5,352,291	10/04/94	Zhang et al					
	5,420,048	05/30/95	Kondo					
	5,529,937	06/25/96	Zhang et al					
	5,530,265	06/25/96	Takemura					
	5,696,011	12/09/97	Yamazaki et al					
	OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)							
		G. Kawachi et al., "Large-Area Doping Process for Fabrication of poly-Si Thin Film Transistors Using Bucket Ion Source and XeCl Excimer Laser Annealing", Japanese Journal of Applied Physics, Vol. 29, No. 12, December 1990, pp. L2370-L2372						
		Examiner Initial	Date Considered	11/10/08				
	*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if no and not considered. Include copy of this form with next communication to applicant.							

OCT. 5 2004 4:14PM

866 751 0075

NO. 1081 P. 10

Sheet 7 of 7

Form PTO-1449
(Rev. 8-83)U.S. Department of Commerce
Patent and Trademark OfficeAttorney Docket: 740756-
2646

Serial No. 10/642,305

INFORMATION DISCLOSURE STATEMENT

(Use several sheets if necessary)

Applicant: Hongyong ZHANG et al.

Filing Date: August 18, 2003 Group: 2811

FOREIGN PATENT DOCUMENTS

Document Number	Date	Country	Class	Subclass	Translation	
					Yes	No
57-109377	07/07/82	Japan			Abstract	
58-002073	01/07/83	Japan			Full	
58-182816	10/25/83	Japan			Abstract	
59-040580	03/06/84	Japan			Abstract	
59-108360	06/22/84	Japan			Abstract	
61-183970	08/16/86	Japan			Abstract	
62-030379	02/09/87	Japan			Abstract	
62-104171	05/14/87	Japan			Full	
62-152171	07/07/87	Japan			Abstract	
62-171160	07/28/87	Japan			Abstract	
62-254466	11/06/87	Japan			Full	
62-286282	12/12/87	Japan			Abstract	
63-000164	01/05/88	Japan			Abstract	
63-168052	07/12/88	Japan			Abstract	
63-172470	07/16/88	Japan			Abstract	
63-301518	12/08/88	Japan			Abstract	
01-313943	12/19/89	Japan			Abstract	
02-033934	02/05/90	Japan			Abstract	
02-090568	03/30/90	Japan			Abstract	
02-177443	07/10/90	Japan			Full	
02-310932	12/26/90	Japan			Abstract	
03-201538	09/03/91	Japan			Abstract	
04-360580	12/14/92	Japan			Abstract	
0 416 798 A2	08/28/90	Europe			Full	
0 439 199 A2	05/07/91	Europe			Full	
2 087 147 A	05/19/82	Great Britain			Full	

Examiner

Dingley - Owen

Date Considered 11/10/04

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

NVA274468.1

PAGE 10/10 *RCVD AT 10/5/2004 4:08:41 PM (Eastern Daylight Time) *SVR:USPTO-EFXRF-1/0 *DNIS:8729306 *CSID:703 880 0669 *DURATION (mm:ss):02:54

**This Page is Inserted by IFW Indexing and Scanning
Operations and is not part of the Official Record**

BEST AVAILABLE IMAGES

Defective images within this document are accurate representations of the original documents submitted by the applicant.

Defects in the images include but are not limited to the items checked:

- BLACK BORDERS**
- IMAGE CUT OFF AT TOP, BOTTOM OR SIDES**
- FADED TEXT OR DRAWING**
- BLURRED OR ILLEGIBLE TEXT OR DRAWING**
- SKEWED/SLANTED IMAGES**
- COLOR OR BLACK AND WHITE PHOTOGRAPHS**
- GRAY SCALE DOCUMENTS**
- LINES OR MARKS ON ORIGINAL DOCUMENT**
- REFERENCE(S) OR EXHIBIT(S) SUBMITTED ARE POOR QUALITY**
- OTHER: _____**

IMAGES ARE BEST AVAILABLE COPY.

As rescanning these documents will not correct the image problems checked, please do not report these problems to the IFW Image Problem Mailbox.